

Search Notes

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10/757,274

Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	119, 122, 130-131, 137, 238	3/27/2007	HP
	241-244		
	256-258		
250	236	3/27/2007	HP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Text Search	3/27/2007	HP